

## Lect. HALİL İBRAHİM EFKERE

### Personal Information

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### Education Information

Doctorate, Gazi University, Fen Bilimleri Enstitüsü, Metalurji Ve Malzeme Mühendisliği (Dr), Turkey 2015 - Continues

Post Graduate, Erciyes University, Fen Bilimleri Enstitüsü, Fizik (YI) (Tezli), Turkey 2010 - 2014

Under Graduate, Selcuk University, Faculty Of Science, Department Of Physics, Turkey 2005 - 2009

### Foreign Languages

English, C1 Advanced

### Dissertations

Post Graduate, InGaAs/GaAs süperörgü yapılarının moleküler demet epitaksi (MBE) tekniğiyle büyütülmesi ve karakterizasyonu, Erciyes University, Fen Bilimleri Enstitüsü, Fizik (YI) (Tezli), 2013

### Research Areas

Physics, Engineering and Technology

### Academic Titles / Tasks

Lecturer, Gazi University, Fotonik Uygulama Ve Araştırma Merkezi, 2020 - Continues

### Articles Published in Journals That Entered SCI, SSCI and AHCI Indexes

- I. **Investigations of some physical properties of ALD growth ZnO films: effect of crystal orientation on photocatalytic activity**  
POLAT GÖNÜLLÜ M., Cergel M. S., EFKERE H. İ., ATEŞ H.  
JOURNAL OF MATERIALS SCIENCE-MATERIALS IN ELECTRONICS, 2021 (Journal Indexed in SCI)
- II. **Electrical Properties of MOS Capacitor with TiO<sub>2</sub>/SiO<sub>2</sub> Dielectric Layer**  
Cetin S. Ş., Efkere H. İ., Sertel T., Tataroğlu A., Özçelik S.  
SILICON, vol.12, no.12, pp.2879-2883, 2020 (Journal Indexed in SCI)
- III. **The effect of thickness on surface structure of rf sputtered TiO<sub>2</sub> thin films by XPS, SEM/EDS, AFM and SAM**  
Guzelcimen F., Tanoren B., Cetinkaya C., Kaya M. D., Efkere H. İ., Özen Y., Bingol D., Sirkeci M., Kinaci B., Ünlü M. B., et al.

VACUUM, vol.182, 2020 (Journal Indexed in SCI)

**IV. Gas Sensing Properties of Cr Doped TiO<sub>2</sub> Films Against Propane**

Comert Sertel B., Efker H. İ. , Özçelik S.

IEEE SENSORS JOURNAL, vol.20, pp.13436-13443, 2020 (Journal Indexed in SCI)

**V. Negative capacitance phenomena in Au/SrTiO<sub>3</sub>/p-Si heterojunction structure**

Kınacı B., Çetinkaya Ç., Çokduygulular E., Efker H. İ. , Akın Sönmez N., Özçelik S.

JOURNAL OF MATERIALS SCIENCE-MATERIALS IN ELECTRONICS, vol.31, pp.8718-8726, 2020 (Journal Indexed in SCI)

**VI. The effect of thickness on the optical, structural and electrical properties of ZnO thin film deposited on n-type Si**

Efker H. İ. , Tataroğlu A., Cetin S. Ş. , Topaloglu N., Gonullu M., Ateş H.

JOURNAL OF MOLECULAR STRUCTURE, vol.1165, pp.376-380, 2018 (Journal Indexed in SCI)

**VII. Surface structure and photoluminescence properties of AZO thin films on polymer substrates**

Akın Sönmez N., Özen Y., Efker H. İ. , Çakmak M., Özçelik S.

SURFACE AND INTERFACE ANALYSIS, vol.47, pp.93-98, 2015 (Journal Indexed in SCI)

## Articles Published in Other Journals

**I. Investigation of the Structural, Morphological, Optical and Electrical Properties of In<sub>2</sub>O<sub>3</sub> Thin Films: Gas Sensor Applications**

Asar T., Korkmaz B., Efker H. İ. , Akın Sönmez N., Özçelik S.

JOURNAL OF POLYTECHNIC-POLITEKNIK DERGISI, vol.21, pp.265-271, 2018 (Journal Indexed in ESCI)

**II. Structural and Optical Properties of Reactive Sputtered ZnO Thin Films on Flexible-Transparent Substrates**

Akın Sönmez N., Başköse Ü. C. , Efker H. İ. , Sağlam S., Aydın S. Ş. , Özçelik S.

GAZI UNIVERSITY JOURNAL OF SCIENCE, vol.27, no.4, pp.1111-1114, 2014 (Refereed Journals of Other Institutions)

## Refereed Congress / Symposium Publications in Proceedings

**I. Synthesis and Characterization of Al<sub>2</sub>O<sub>3</sub> Thin Film By Using Atomic Layer Deposition**

ÇOLAK T., KUPA İ., ÖZKAN Ö. B. , ÜNAL Y., EFKER H. İ. , POLAT GÖNÜLLÜ M., ATEŞ H.

8th International Advanced Technologies Symposium, 19 - 22 October 2017

## Citations

Total Citations (WOS):42

h-index (WOS):3